

June 1989

2K x 8 CMOS PROM

Features

- This Circuit is Processed in Accordance to MIL-STD-883 and is Fully Conformant Under the Provisions of Paragraph 1.2.1.
- Low Power Standby and Operating Power
 - ▶ ICCSB 100 μ A
 - ▶ ICCOP 20mA at 1MHz
- Fast Access Time 90/120ns
- Industry Standard Pinout
- Single 5.0 Volt Supply
- CMOS/TTL Compatible Inputs
- High Output Drive 12 LSTTL Loads
- Synchronous Operation
- On-Chip Address Latches
- Separate Output Enable
- Operating Temperature Range -55 $^{\circ}$ C to +125 $^{\circ}$ C

Description

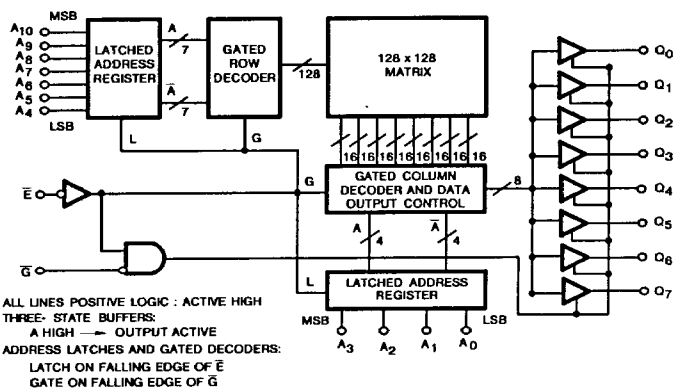
The HM-6617/883 is a 16,384 bit fuse link CMOS PROM in a 2K word by 8 bit/word format with "Three-State" outputs. This PROM is available in the standard 0.600 inch wide 24 pin Ceramic DIP, the 0.300 inch wide slimline Ceramic DIP, and the JEDEC standard 32 pad Ceramic LCC.

The HM-6617/883 utilizes a synchronous design technique. This includes on-chip address latches and a separate output enable control which makes this device ideal for applications utilizing recent generation microprocessors. This design technique, combined with the Harris advanced self-aligned silicon gate CMOS process technology offers ultra-low standby current. Low ICCSB is ideal for battery applications or other systems with low power requirements.

The Harris NiCr fuse link technology is utilized on this and other Harris CMOS PROMs. This gives the user a PROM with permanent, stable storage characteristics over the full industrial and military temperature voltage ranges. NiCr fuse technology combined with the low power characteristics of CMOS provides an excellent alternative to standard bipolar PROMs or NMOS EPROMs.

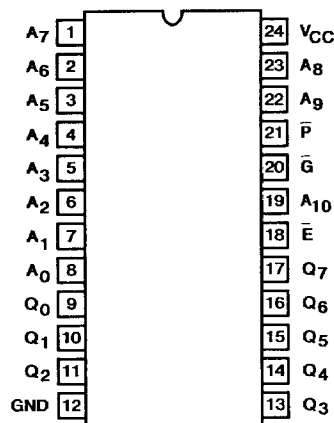
All bits are manufactured storing a logical "0" and can be selectively programmed for a logical "1" at any bit location.

Functional Diagram

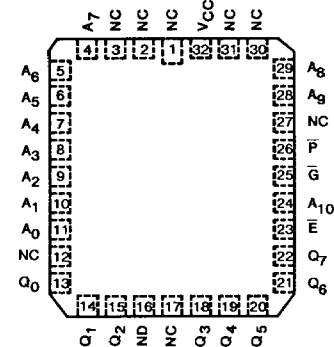


Pinouts

HM1-6617/883 (CERAMIC DIP)
TOP VIEW



HM4-6617/883 (CERAMIC LCC)
TOP VIEW



PIN	DESCRIPTION
NC	No Connect
A ₀ - A ₁₀	Address Inputs
\bar{E}	Chip Enable
Q	Data Input
VCC	Power (+5V)
\bar{G}	Output Enable
\bar{P}^*	Program Enable

* \bar{P} Should be Hardwired to VCC Except During Programming

Specifications HM-6617/883

Absolute Maximum Ratings

Supply Voltage (All Voltages Reference to Device GND) +7.0V
 Input or Output Voltage Applied for all Grades GND-0.3V to $V_{CC}+0.3V$
 Storage Temperature Range -65°C to +150°C
 Lead Temperature (Soldering 10 sec) +300°C
 Junction Temperature +175°C
 ESD Classification Class 1
 Typical Derating Factor 5mA/MHz Increase in ICCOP

Reliability Information

Thermal Resistance θ_{ja} θ_{jc}
 Ceramic DIP Package 48°C/W 9°C/W
 Ceramic LCC Package 58°C/W 19°C/W
 Maximum Package Power Dissipation at +125°C
 Ceramic DIP Package 1.0W
 Ceramic LCC Package 0.86W
 Gate Count 5473 Gates

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

Operating Conditions

Operating Supply Voltage (V_{CC}) 4.5V to 5.5V Input Low Voltage (V_{IL}) -0.3V to +0.8V
 Operating Temperature (T_A) -55°C to +125°C Input High Voltage (V_{IH}) +2.4V to $V_{CC}+0.3V$

TABLE 1. HM-6617/883 D.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Guaranteed and 100% Tested

D.C. PARAMETERS	SYMBOL	(NOTES 1, 4) CONDITIONS	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
High Level Output Voltage	V_{OH1}	$V_{CC} = 4.5V$, $I_O = -2.0mA$	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	2.4	-	V
Low Level Output Voltage	V_{OL}	$V_{CC} = 4.5V$, $I_O = +4.8mA$	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-	0.4	V
High Impedance Output Leakage Current	I_{IOZ}	$V_{CC} = 5.5V$, $\bar{G} = 5.5V$, $V_I/O = GND$ or V_{CC}	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-1.0	1.0	μA
Input Leakage Current	I_I	$V_{CC} = 5.5V$, $V_I = GND$ or V_{CC} , \bar{P} Not Tested	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-1.0	1.0	μA
Standby Supply Current	ICCSB	$V_I = V_{CC}$ or GND, $V_{CC} = 5.5V$, $I_O = 0mA$	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-	100	μA
Operating Supply Current	ICCOP	$V_{CC} = 5.5V$, $\bar{G} = GND$, (Note 3), $f = 1 MHz$, $I_O = 0mA$, $V_I = V_{CC}$ or GND	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-	20	mA
Functional Test	FT	$V_{CC} = 4.5V$ (Note 12)	7, 8A, 8B	$-55^\circ C \leq T_A \leq +125^\circ C$	-	-	

TABLE 2. HM-6617/883 A.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Guaranteed and 100% Tested

A.C. PARAMETERS	SYMBOL	(NOTES 1, 2, 4) CONDITIONS	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Address Access Time	TAVQV	$V_{CC} = 4.5V$ and 5.5V (Note 5)	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	-	140	ns
Output Enable Access Time	TGLQV	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	-	50	ns
Chip Enable Access Time	TELQV	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	-	120	ns
Address Setup Time	TAVEL	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	20	-	ns
Address Hold Time	TELAX	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	25	-	ns
Chip Enable Low Width	TELEH	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	120	-	ns
Chip Enable High Width	TEHEL	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	40	-	ns
Read Cycle Time	TELEL	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	160	-	ns

NOTES: 1. All voltages referenced to Device GND.

2. AC measurements assume transition time $\leq 5ns$; input levels = 0.0V to 3.0V; timing reference levels = 1.5V; output load = 1TTL equivalent load and $CL = 50pF$.

3. Typical derating = 5mA/MHz increase in ICCOP.

4. All tests performed with \bar{P} hardwired to V_{CC} .

5. TAVQV = TELQV + TAVEL

CAUTION: These devices are sensitive to electronic discharge. Proper I.C. handling procedures should be followed.

Specifications HM-6617/883

TABLE 3. HM-6617/883 A.C. AND D.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

PARAMETERS	SYMBOL	(NOTE 4) CONDITIONS	NOTES	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Input Capacitance	C_{IN}	$V_{CC} = \text{Open}, f = 1\text{MHz}$, All Measurements Referenced to Device GND	6, 9	+25°C	-	10	pF
		$V_{CC} = \text{Open}, f = 1\text{MHz}$, All Measurements Referenced to Device GND	6, 10	+25°C	-	12	pF
		$V_{CC} = \text{Open}, f = 1\text{MHz}$, All Measurements Referenced to Device GND	6, 11	+25°C	-	10	pF
I/O Capacitance	$C_{I/O}$	$V_{CC} = \text{Open}, f = 1\text{MHz}$, All Measurements Referenced to Device GND	6, 9	+25°C	-	12	pF
		$V_{CC} = \text{Open}, f = 1\text{MHz}$, All Measurements Referenced to Device GND	6, 10	+25°C	-	14	pF
		$V_{CC} = \text{Open}, f = 1\text{MHz}$, All Measurements Referenced to Device GND	6, 11	+25°C	-	12	pF
Chip Enable Time	TELQX	$V_{CC} = 4.5\text{V and } 5.5\text{V}$	6	$-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$	5	-	ns
Output Enable Time	TGLQX	$V_{CC} = 4.5\text{V and } 5.5\text{V}$	6	$-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$	5	-	ns
Chip Disable Time	TEHQZ	$V_{CC} = 4.5\text{V and } 5.5\text{V}$	6	$-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$	-	50	ns
Output Disable Time	TGHQZ	$V_{CC} = 4.5\text{V and } 5.5\text{V}$	6	$-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$	-	50	ns
Output High Voltage	V_{OH2}	$V_{CC} = 4.5\text{V}, I_O = 100\mu\text{A}$	6	$-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$	$V_{CC} - 1\text{V}$	-	V

NOTES: 6. The parameters listed in table 3 are controlled via design or process parameters and are not directly tested. These parameters are characterized upon initial design and after design or process changes which would affect these characteristics.

7. Tested as follows: $f = 2\text{MHz}$, $V_{IH} = 2.4\text{V}$, $V_{IL} = 0.4\text{V}$, $I_{OH} = -4.0\text{mA}$, $V_{OH} \geq 1.5\text{V}$, and $V_{OL} \leq 1.5\text{V}$.

8. This is a "typical" value and not a "maximum" value.

9. Applies to .600 inch Ceramic Dual-In-Line (DIP) device types only.

10. Applies to .300 inch Ceramic Dual-In-Line (DIP) device types only.

11. Applies to Ceramic Leadless Chip Carrier (LCC) device types only.

12. Tested as follows: $f = 1\text{MHz}$, $V_{IH} = 2.4\text{V}$, $V_{IL} = 0.8\text{V}$, $I_{OH} = -1\text{mA}$, $I_{OL} = +1\text{mA}$, $V_{OH} \geq 1.5\text{V}$, $V_{OL} \leq 1.5\text{V}$.

TABLE 4. APPLICABLE SUBGROUPS

CONFORMANCE GROUPS	METHOD	SUBGROUPS
Initial Test	100%/5004	-
Interim Test	100%/5004	1, 7, 9
PDA	100%/5004	1
Final Test	100%/5004	2, 3, 8A, 8B, 10, 11
Group A	Samples/5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11
Groups C & D	Samples/5005	1, 7, 9

Specifications HM-6617B/883

Absolute Maximum Ratings

Supply Voltage (All Voltages Reference to Device GND) +7.0V
 Input or Output Voltage Applied for all Grades GND-0.3V to $V_{CC}+0.3V$
 Storage Temperature Range -65°C to +150°C
 Lead Temperature (Soldering 10 sec) +300°C
 Junction Temperature +175°C
 ESD Classification Class 1
 Typical Derating Factor 5mA/MHz Increase in ICCOP

Reliability Information

Thermal Resistance θ_{ja} θ_{jc}
 Ceramic DIP Package 48°C/W 9°C/W
 Ceramic LCC Package 58°C/W 19°C/W
 Maximum Package Power Dissipation at +125°C
 Ceramic DIP Package 1.0W
 Ceramic LCC Package 0.86W
 Gate Count 5473 Gates

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

Operating Conditions

Operating Supply Voltage (V_{CC}) 4.5V to 5.5V Input Low Voltage (V_{IL}) -0.3V to +0.8V
 Operating Temperature (T_A) -55°C to +125°C Input High Voltage (V_{IH}) +2.4V to $V_{CC}+0.3V$

TABLE 1. HM-6617B/883 D.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Guaranteed and 100% Tested

D.C. PARAMETERS	SYMBOL	(NOTES 1, 4) CONDITIONS	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
High Level Output Voltage	V_{OH1}	$V_{CC} = 4.5V$, $I_O = -2.0mA$	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	2.4	-	V
Low Level Output Voltage	V_{OL}	$V_{CC} = 4.5V$, $I_O = +4.8mA$	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-	0.4	V
High Impedance Output Leakage Current	IIOZ	$V_{CC} = 5.5V$, $\bar{G} = 5.5V$, $V_{I/O} = GND$ or V_{CC}	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-1.0	1.0	μA
Input Leakage Current	II	$V_{CC} = 5.5V$, $V_I = GND$ or V_{CC} , P Not Tested	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-1.0	1.0	μA
Standby Supply Current	ICCSB	$V_I = V_{CC}$ or GND, $V_{CC} = 5.5V$, $I_O = 0mA$	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-	100	μA
Operating Supply Current	ICCOP	$V_{CC} = 5.5V$, $\bar{G} = GND$, (Note 3), $f = 1MHz$, $I_O = 0mA$, $V_I = V_{CC}$ or GND	1, 2, 3	$-55^\circ C \leq T_A \leq +125^\circ C$	-	20	mA
Functional Test	FT	$V_{CC} = 4.5V$ (Note 12)	7, 8A, 8B	$-55^\circ C \leq T_A \leq +125^\circ C$	-	-	

TABLE 2. HM-6617B/883 A.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Guaranteed and 100% Tested

A.C. PARAMETERS	SYMBOL	(NOTES 1, 2, 4) CONDITIONS	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Address Access Time	TAVQV	$V_{CC} = 4.5V$ and 5.5V (Note 5)	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	-	105	ns
Output Enable Access Time	TGLQV	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	-	40	ns
Chip Enable Access Time	TELOV	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	-	90	ns
Address Setup Time	TAVEL	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	15	-	ns
Address Hold Time	TELEX	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	20	-	ns
Chip Enable Low Width	TELEH	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	95	-	ns
Chip Enable High Width	TEHEL	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	40	-	ns
Read Cycle Time	TELEL	$V_{CC} = 4.5V$ and 5.5V	9, 10, 11	$-55^\circ C \leq T_A \leq +125^\circ C$	136	-	ns

NOTES: 1. All voltages referenced to Device GND.

2. AC measurements assume transition time $\leq 5ns$; input levels = 0.0V to 3.0V; timing reference levels = 1.5V; output load = 1TTL equivalent load and $C_L \approx 50pF$.

3. Typical derating = 5mA/MHz increase in ICCOP.

4. All tests performed with P hardwired to V_{CC} .

5. TAVQV = TELOV + TAVEL

CAUTION: These devices are sensitive to electronic discharge. Proper I.C. handling procedures should be followed.

Specifications HM-6617B/883

TABLE 3. HM-6617B/883 A.C. AND D.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

PARAMETERS	SYMBOL	(NOTE 4) CONDITIONS	NOTES	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Input Capacitance	C _{IN}	V _{CC} = Open, f = 1 MHz, All Measurements Referenced to Device GND	6, 9	+25°C	-	10	pF
		V _{CC} = Open, f = 1 MHz, All Measurements Referenced to Device GND	6, 10	+25°C	-	12	pF
			6, 11	+25°C	-	10	pF
I/O Capacitance	C _{I/O}	V _{CC} = Open, f = 1 MHz, All Measurements Referenced to Device GND	6, 9	+25°C	-	12	pF
		V _{CC} = Open, f = 1 MHz, All Measurements Referenced to Device GND	6, 10	+25°C	-	14	pF
			6, 11	+25°C	-	12	pF
Chip Enable Time	TELQX	V _{CC} = 4.5V and 5.5V	6	-55°C ≤ T _A ≤ +125°C	5	-	ns
Output Enable Time	TGLQX	V _{CC} = 4.5V and 5.5V	6	-55°C ≤ T _A ≤ +125°C	5	-	ns
Chip Disable Time	TEHQZ	V _{CC} = 4.5V and 5.5V	6	-55°C ≤ T _A ≤ +125°C	-	45	ns
Output Disable Time	TGHQZ	V _{CC} = 4.5V and 5.5V	6	-55°C ≤ T _A ≤ +125°C	-	40	ns
Output High Voltage	V _{OH2}	V _{CC} = 4.5V, I _O = 100μA	6	-55°C ≤ T _A ≤ +125°C	V _{CC} - 1V	-	V

NOTES: 6. The parameters listed in table 3 are controlled via design or process parameters and are not directly tested. These parameters are characterized upon initial design changes which would affect these characteristics.

7. Tested as follows: f = 2MHz, V_{IH} = 2.4V, V_{IL} = 0.4V, I_{OH} = -4.0mA, V_{OH} ≥ 1.5V, and V_{OL} ≤ 1.5V.

8. This is a typical" value and not a maximum" value.

9. Applies to .600 inch Ceramic Dual-In-Line (DIP) device types only.

10. Applies to .300 inch Ceramic Dual-In-Line (DIP) device types only.

11. Applies to Ceramic Leadless Chip Carrier (LCC) device types only.

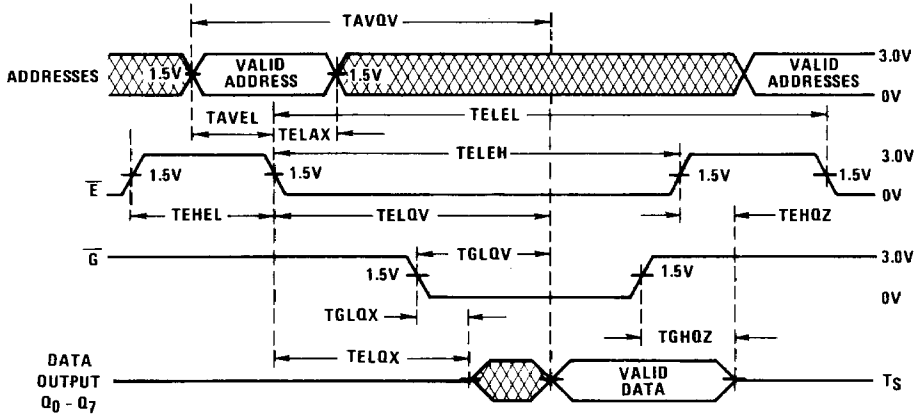
12. Tested as follows: f = 1MHz, V_{IH} = 2.4V, V_{IL} = 0.8V, I_{OH} = -1mA, I_{OL} = +1mA, V_{OH} ≥ 1.5V, V_{OL} ≤ 1.5V.

TABLE 4. APPLICABLE SUBGROUPS

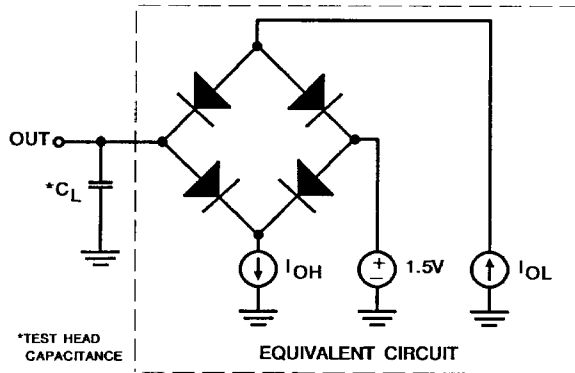
CONFORMANCE GROUPS	METHOD	SUBGROUPS
Initial Test	100%/5004	-
Interim Test	100%/5004	1, 7, 9
PDA	100%/5004	1
Final Test	100%/5004	2, 3, 8A, 8B, 10, 11
Group A	Samples/5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11
Groups C & D	Samples/5005	1, 7, 9

Switching Waveforms

READ CYCLE



Test Circuit

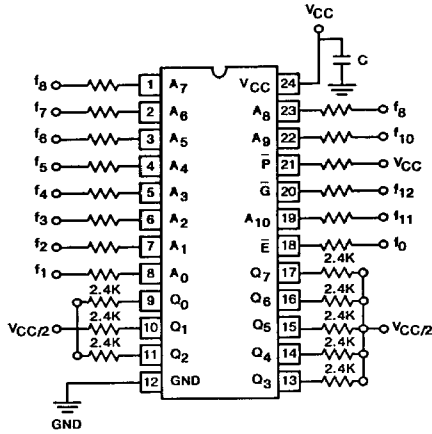


3
CMOS
MEMORY

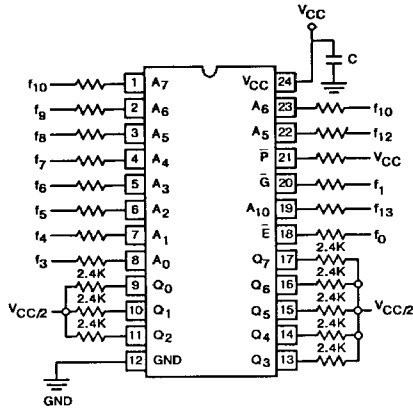
HM-6617/883

Burn-In Circuits

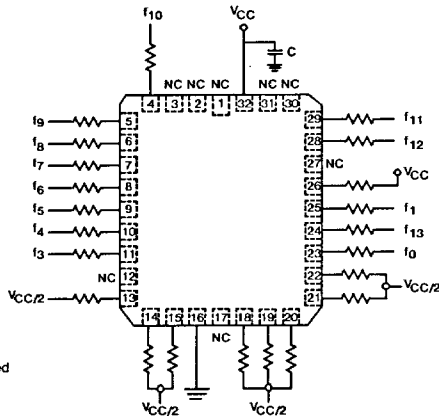
HM-6617/883 (.300 INCH) CERAMIC DIP



HM-6617/883 (.600) CERAMIC DIP



HM-6617/883 CERAMIC LCC



NOTES:

- $f_0 = 100\text{kHz} \pm 10\%$
- All resistors = $47\text{k}\Omega$ Unless Otherwise Noted
- $V_{CC} = 5.5\text{V} \pm 0.05\text{V}$
- $C = 0.01\mu\text{F min}$

Metallization Topology

DIE DIMENSIONS:

140 x 232 x 19 ± 1 mils

METALLIZATION:

Type: Si - Al

Thickness: 11kÅ - 15kÅ

GLASSIVATION:

Type: SiO₂

Thickness: 7kÅ - 9kÅ

DIE ATTACH:

Material: Si - Au Eutectic

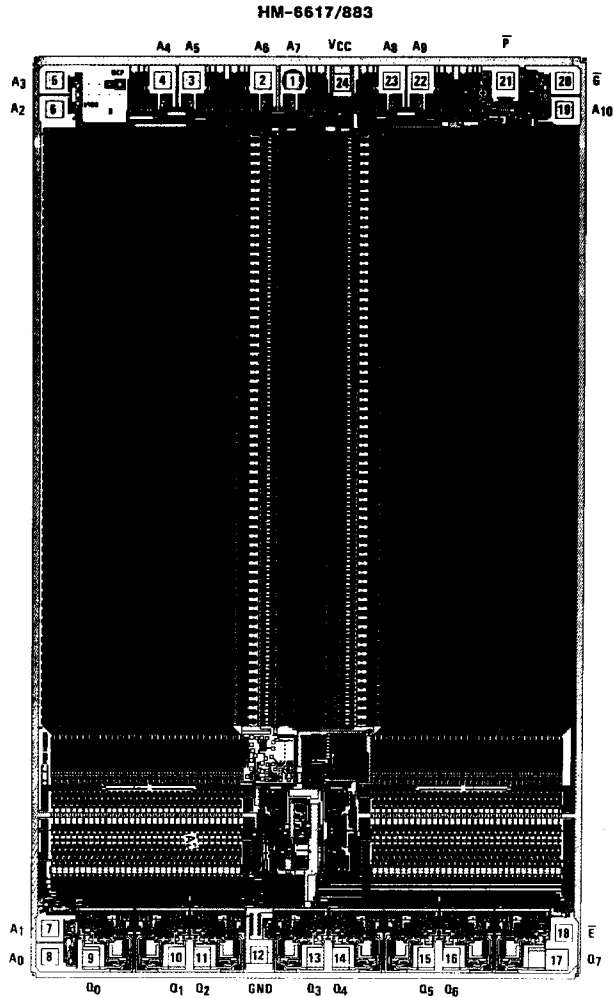
Temperature: Ceramic DIP — 460°C (Max)

Ceramic LCC — 420°C (Max)

WORST CASE CURRENT DENSITY:

1.7 x 10⁵ A/cm²

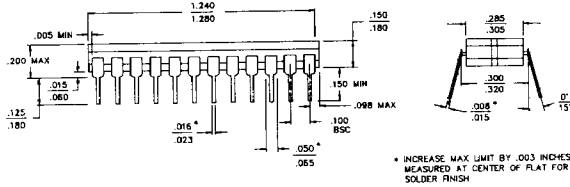
Metallization Mask Layout



3
CMOS
MEMORY

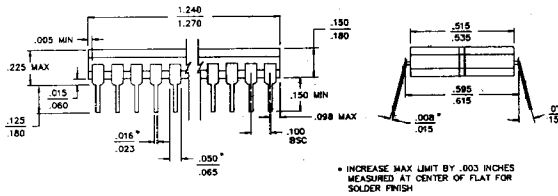
Packaging †

24 PIN (.300) CERAMIC DIP



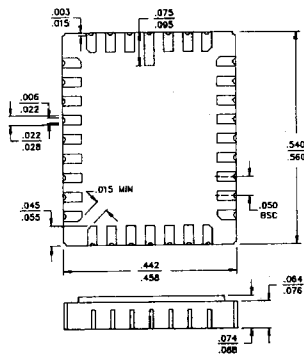
LEAD MATERIAL: Type B
LEAD FINISH: Type A
PACKAGE MATERIAL: Ceramic, 90% Alumina
PACKAGE SEAL:
 Material: Glass Frit
 Temperature: 450°C ± 10°C
 Method: Furnace Seal
INTERNAL LEAD WIRE:
 Material: Aluminum
 Diameter: 1.25 Mil
 Bonding Method: Ultrasonic
COMPLIANT OUTLINE: 38510 D-9

24 PIN (.600) CERAMIC DIP



LEAD MATERIAL: Type B
LEAD FINISH: Type A
PACKAGE MATERIAL: Ceramic, 90% Alumina
PACKAGE SEAL:
 Material: Glass Frit
 Temperature: 450°C ± 10°C
 Method: Furnace Seal
INTERNAL LEAD WIRE:
 Material: Aluminum
 Diameter: 1.25 Mil
 Bonding Method: Ultrasonic
COMPLIANT OUTLINE: 38510 D-3

32 PAD CERAMIC LCC



PAD MATERIAL: Type C
PAD FINISH: Type A
FINISH DIMENSION: Type A
PACKAGE MATERIAL: Ceramic Al₂O₃ 90%
PACKAGE SEAL:
 Material: Gold/Tin (80/20)
 Temperature: 320°C ± 10°C
 Method: Furnace Braze
INTERNAL LEAD WIRE:
 Material: Aluminum
 Diameter: 1.25 Mil
 Bonding Method: Ultrasonic
COMPLIANT OUTLINE: 38510 C-12

NOTE: All Dimensions are $\frac{\text{Min}}{\text{Max}}$. Dimensions are in inches.

† Mil-M-38510 Compliant Materials, Finishes, and Dimensions.

DESIGN INFORMATION

2K x 8 CMOS PROM

The information contained in this section has been developed through characterization by Harris Semiconductor and is for use as application and design information only. No guarantee is implied.

Background Information HM-6617 Programming

PROGRAMMING SPECIFICATIONS

SYMBOL	PARAMETER	MIN	TYP	MAX	UNITS	NOTES
V_{IL}	Input "0"	0.0	0.2	0.8	V	
V_{IH}	Voltage "1"	$V_{CC}-2$	V_{CC}	$V_{CC}+0.3$	V	6
V_{CCPROG}	Programming V_{CC}	12.0	12.0	12.5	V	2
V_{CC1}	Operating V_{CC}	4.5	5.5	5.5	V	
V_{CC2}	Special Verify V_{CC}	4.0	-	6.0	V	3
t_d	Delay Time	1.0	1.0	-	μs	
t_r	Rise Time	1.0	10.0	10.0	μs	
t_f	Fall Time	1.0	10.0	10.0	μs	
TEHEL	Chip Enable Pulse Width	50	-	-	ns	
TAVEL	Address Valid to Chip Enable Low Time	20	-	-	ns	
TELQV	Chip Enable Low to Output Valid Time	-	-	120	ns	
t_{pw}	Programming Pulse Width	90	100	110	μs	4
t_{ip}	Input Leakage at $V_{CC} = V_{CCPROG}$	-10	+1.0	10	μA	
I_{OP}	Data Output Current at $V_{CC} = V_{CCPROG}$	-	-5.0	-10	mA	
R_n	Output Pull-Up Resistor	5	10	15	$k\Omega$	5
T_A	Ambient Temperature	-	25	-	$^{\circ}C$	

NOTES:

- All inputs must track V_{CC} (pin 24) within these limits.
- V_{CCPROG} must be capable of supplying 500mA.
- See Steps 22 through 29 of the Programming Algorithm.
- See Step 11 of the Programming Algorithm.
- All outputs should be pulled up to V_{CC} through a resistor of value R_n .
- Except during programming (See Programming Cycle Waveforms).

DESIGN INFORMATION (Continued)

The information contained in this section has been developed through characterization by Harris Semiconductor and is for use as application and design aid only. These characteristics are not 100% tested and no product guarantee is implied.

Background Information Programming Algorithm

The HM-6617 CMOS PROM is manufactured with all bits containing a logical zero (output low). Any bit can be programmed selectively to a logical one (output high) state by following the procedure shown below. To accomplish this, a programmer can be built that meets the specifications shown, or any of the approved commercial programmers can be used.

PROGRAMMING SEQUENCE OF EVENTS

- 1) Apply a voltage of V_{CC1} to V_{CC} of the PROM.
- 2) Read all fuse locations to verify that the PROM is blank (output low).
- 3) Place the PROM in the initial state for programming:
 $\bar{E} = V_{IH}$, $\bar{P} = V_{IH}$, $\bar{G} = V_{IL}$.
- 4) Apply the correct binary address for the word to be programmed. No inputs should be left open circuit.
- 5) After a delay of t_{d} , apply voltage of V_{IL} to \bar{E} (pin 18) to access the addressed word.
- 6) The address may be held through the cycle, but must be held valid at least for a time equal to t_{d} after the falling edge of \bar{E} . None of the inputs should be allowed to float to an invalid logic level.
- 7) After a delay of t_{d} , disable the outputs by applying a voltage of V_{IH} to \bar{G} (pin 20).
- 8) After a delay of t_{d} , apply voltage of V_{IL} to \bar{P} (pin 21).
- 9) After delay of t_{d} , raise V_{CC} (pin 24) to V_{CCPROG} with a rise time of t_r . All outputs at V_{IH} should track V_{CC} with $V_{CC}-2.0V$ to $V_{CC}+0.3V$. This could be accomplished by pulling outputs at V_{IH} to V_{CC} through pull-up resistors of value R_n .
- 10) After a delay of t_{d} , pull the output which corresponds to the bit to be programmed to V_{IL} . Only one bit should be programmed at a time.
- 11) After a delay of t_{pw} , allow the output to be pulled to V_{IH} through pull-up resistor R_n .
- 12) After a delay of t_{d} , reduce V_{CC} (pin 24) to V_{CC1} with a fall time of t_f . All outputs at V_{IH} should track V_{CC} with $V_{CC}-2.0V$ to $V_{CC}+0.3V$. This could be accomplished by pulling outputs at V_{IH} to V_{CC} through pull-up resistors of value R_n .
- 13) Apply a voltage of V_{IH} to \bar{P} (pin 21).
- 14) After a delay of t_{d} , apply a voltage of V_{IL} to \bar{G} (pin 20).
- 15) After a delay of t_{d} , examine the outputs for correct data. If any location verifies incorrectly, repeat steps 4 through 14 (attempting to program only those bits in the word which verified incorrectly) up to a maximum of eight attempts for a given word. If a word does not program within eight attempts, it should be considered a programming reject.
- 16) Repeat steps 3 through 15 for all other bits to be programmed in the PROM.

POST-PROGRAMMING VERIFICATION

- 17) Place the PROM in the post-programming verification mode:
 $\bar{E} = V_{IH}$, $\bar{G} = V_{IL}$, $\bar{P} = V_{IH}$, V_{CC} (pin 24) = V_{CC1} .
- 18) Apply the correct binary address of the word to be verified to the PROM.
- 19) After a delay of t_{d} , apply a voltage of V_{IL} to \bar{E} (pin 18).
- 20) After a delay of t_{d} , examine the outputs for correct data. If any location fails to verify correctly, the PROM should be considered a programming reject.
- 21) Repeat steps 17 through 20 for all possible programming locations.

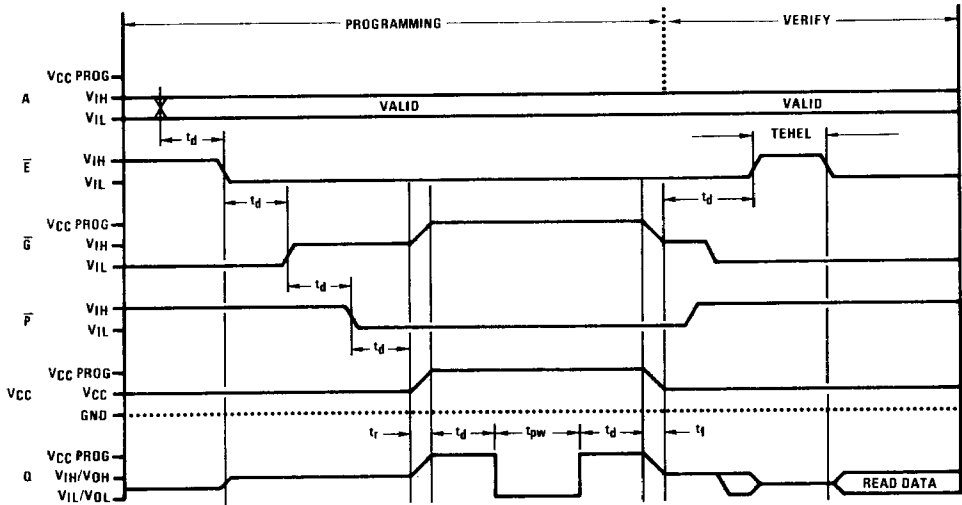
POST-PROGRAMMING READ

- 22) Apply a voltage of $V_{CC2} = 4.0V$ to V_{CC} (pin 24).
- 23) After a delay of t_{d} , apply a voltage of V_{IH} to \bar{E} (pin 18).
- 24) Apply the correct binary address of the word to be read.
- 25) After a delay of TAVEL, apply a voltage of V_{IL} to \bar{E} (pin 18).
- 26) After a delay of TELQV, examine the outputs for correct data. If any location fails to verify correctly, the PROM should be considered a programming reject.
- 27) Repeat steps 23 through 26 for all address locations.
- 28) Apply a voltage of $V_{CC2} = 6.0V$ to V_{CC} (pin 24).
- 29) Repeat steps 23 through 26 for all address locations.

DESIGN INFORMATION (Continued)

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HM-6617 PROGRAMMING CYCLE



HM-6617 POST PROGRAMMING VERIFY CYCLE

